


<b>Search Notes</b>  	<b>Application/Control No.</b>  10541240	<b>Applicant(s)/Patent Under Reexamination</b>  OUCHI, TOSHIHIKO
	<b>Examiner</b>  RYAN LEPISTO	<b>Art Unit</b>  2883

SEARCHED			
Class	Subclass	Date	Examiner
385	4, 8, 12, 40, 41, 45	11/19/08	RAL
359	331, 332	11/19/08	RAL
250	358.1, 393, 227.12	11/19/08	RAL

SEARCH NOTES		
Search Notes	Date	Examiner
See search history - EAST (all databases), non-patent literature (IEEE, OpticsInfoBase)	11/19/08	RAL
Updated search - EAST (all databases), non-patent literature (IEEE, OpticsInfoBase)	4/1/09	RAL
Checked refs from PCT/JP04/04348	4/1/09	RAL
Inventorship searched in PALM	4/1/09	RAL
Consulted the TC 2800 101 Help Panel	4/1/09	RAL

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
385	4, 8, 12, 40, 41, 45	4/1/09	RAL
359	331, 332	4/1/09	RAL
250	358.1, 393, 227.12	4/1/09	RAL

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